

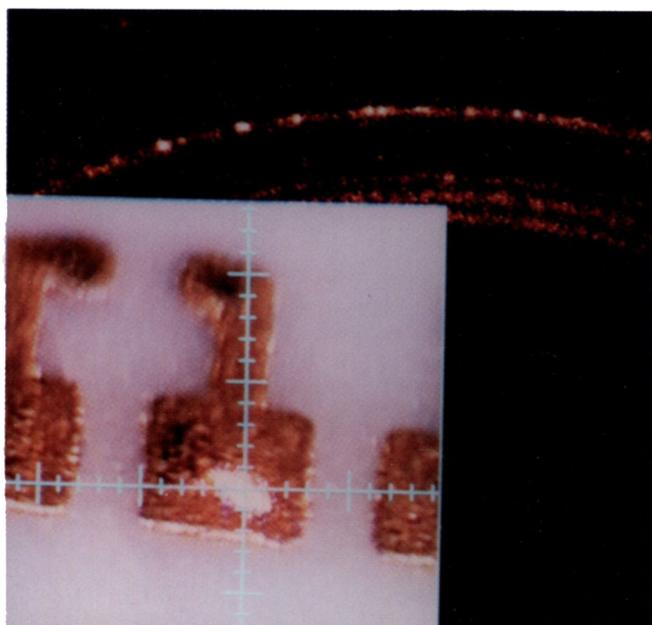


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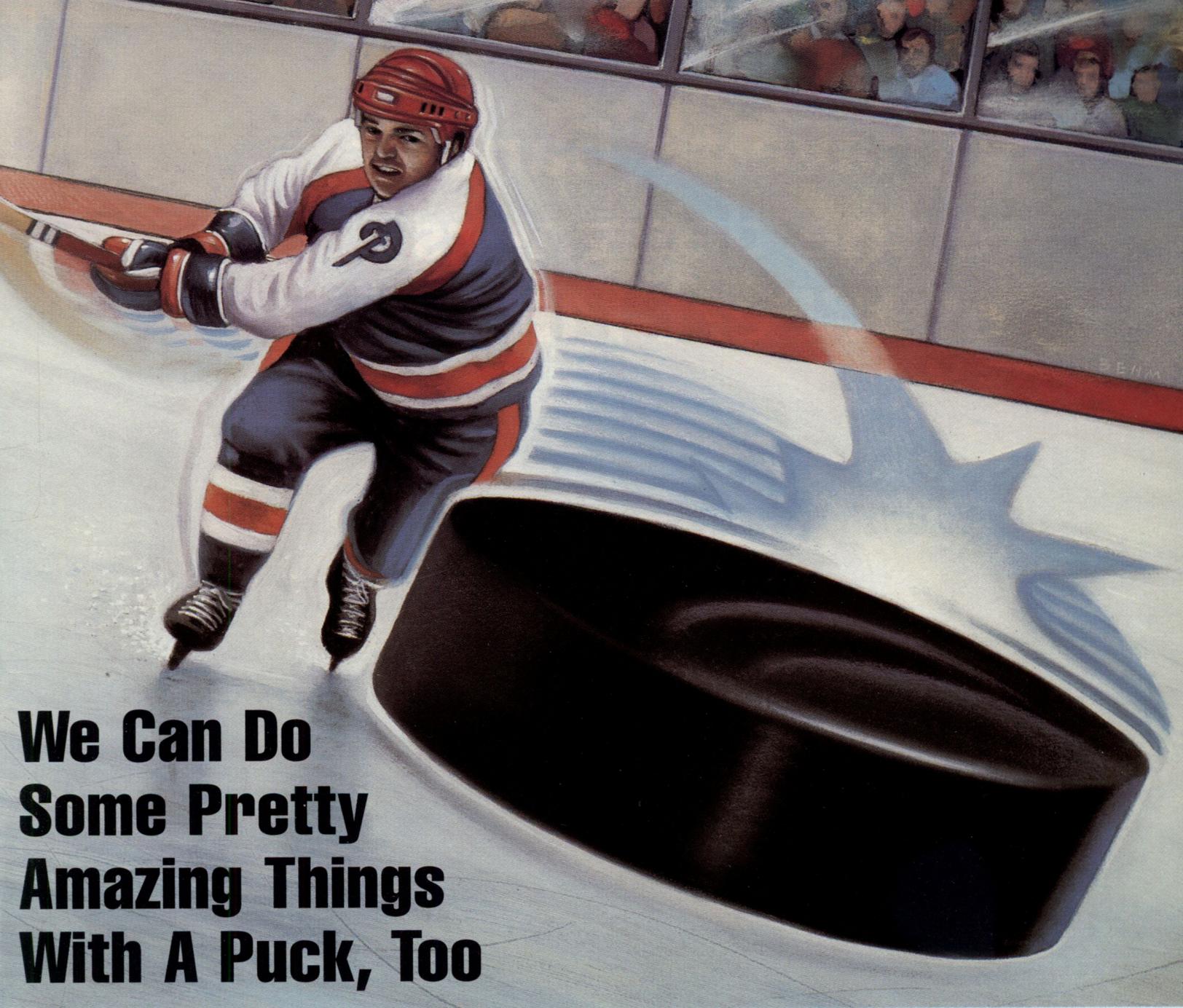
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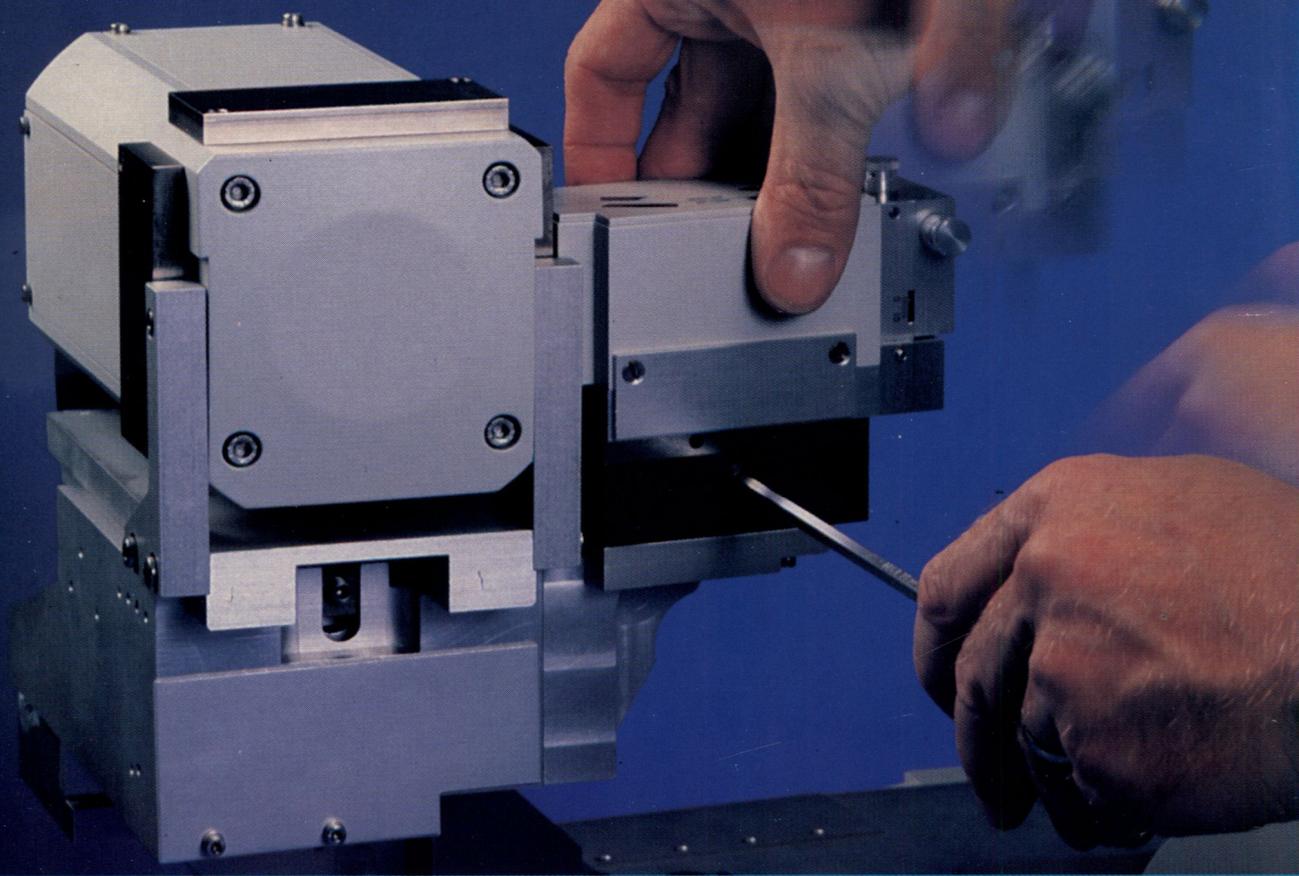
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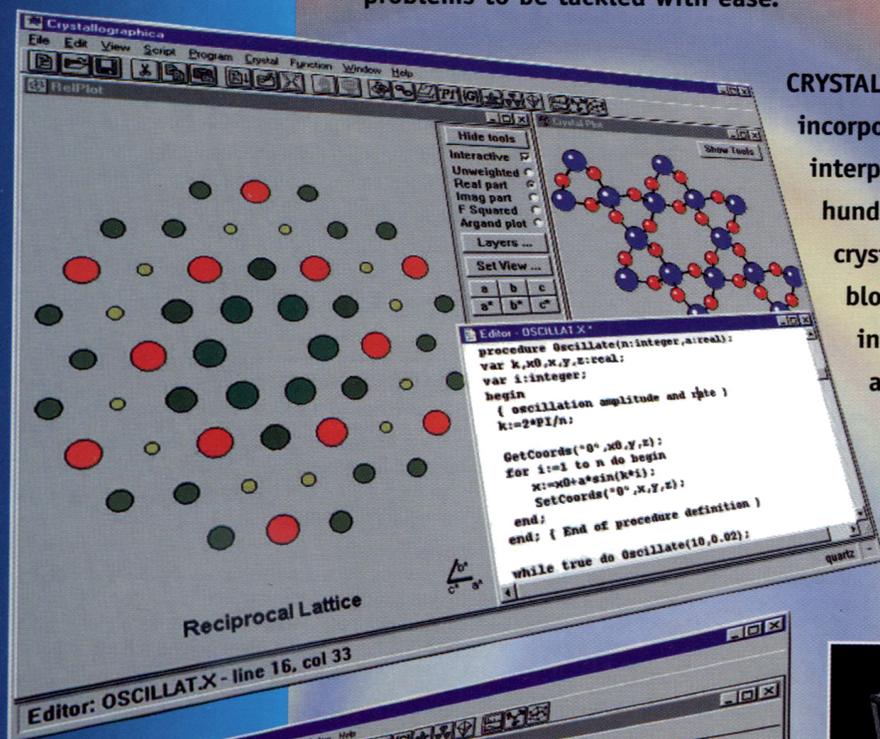
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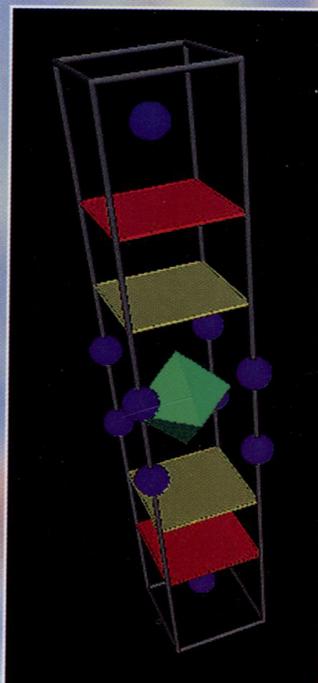
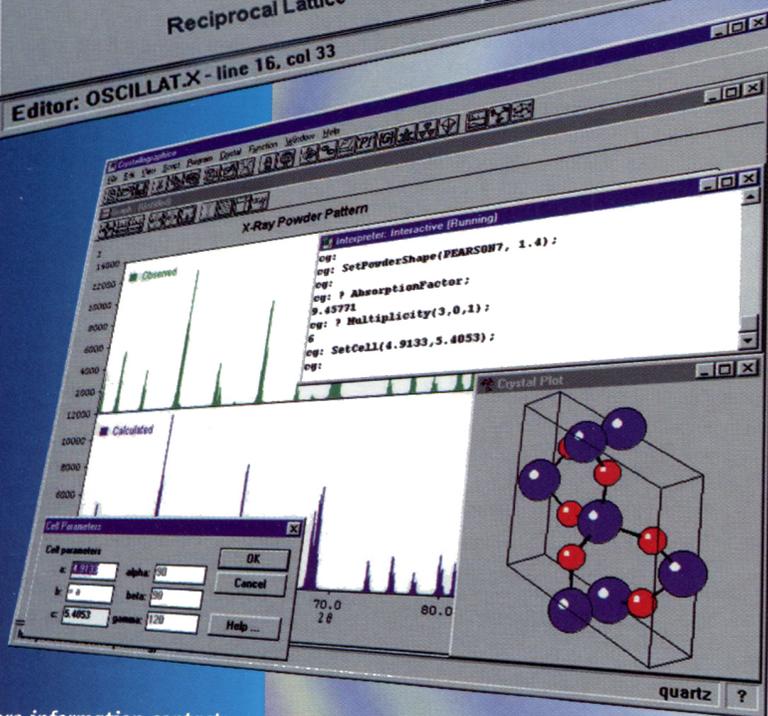


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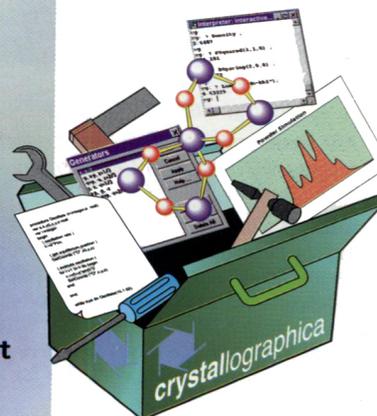
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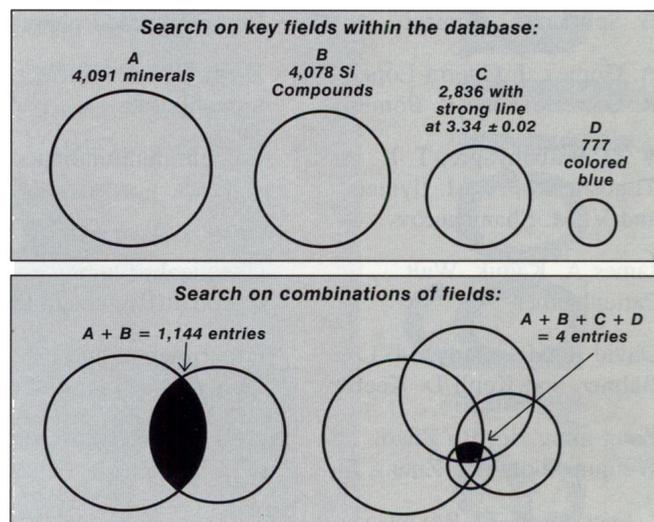
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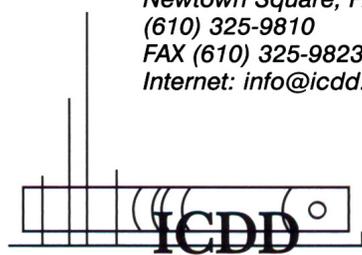
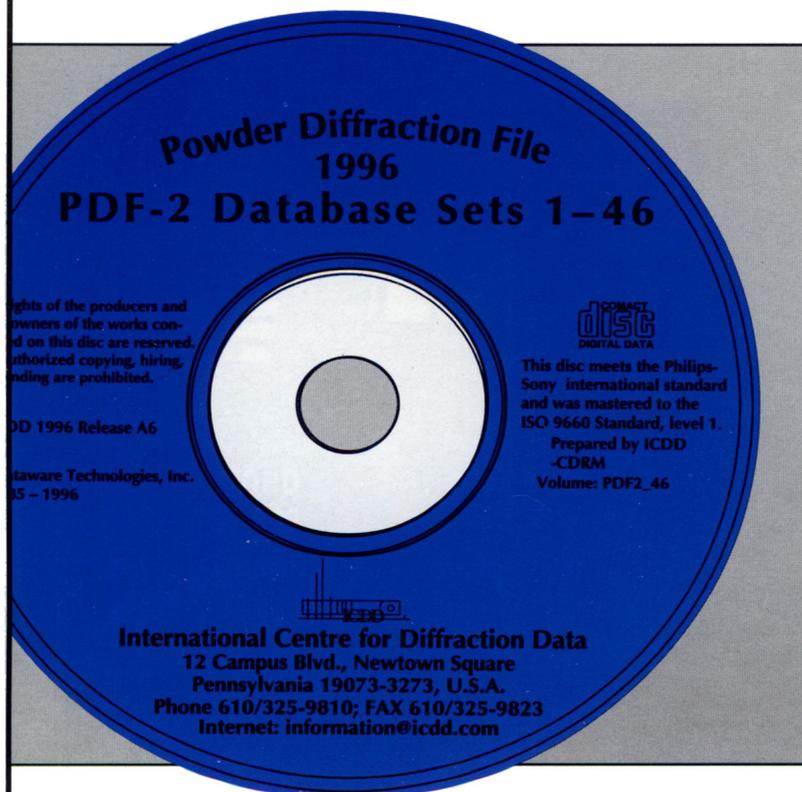


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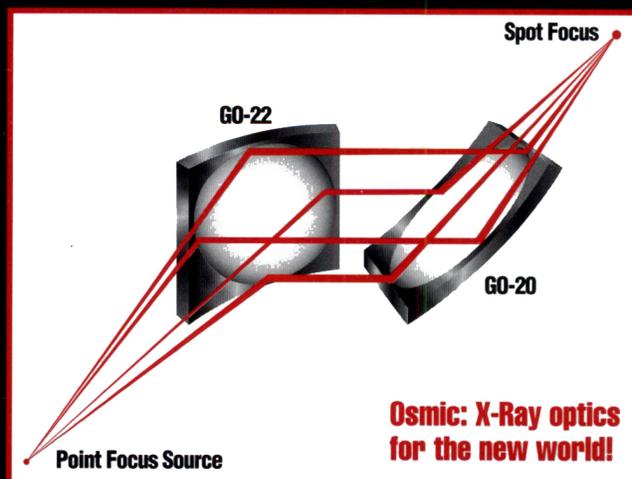
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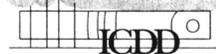
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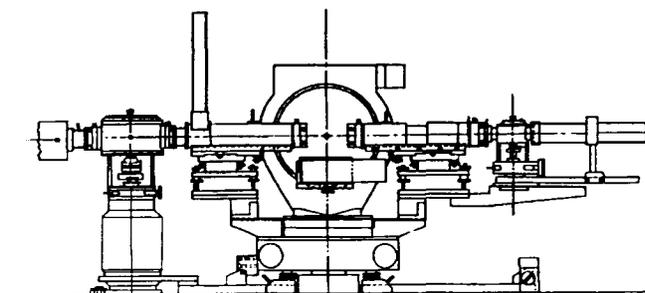
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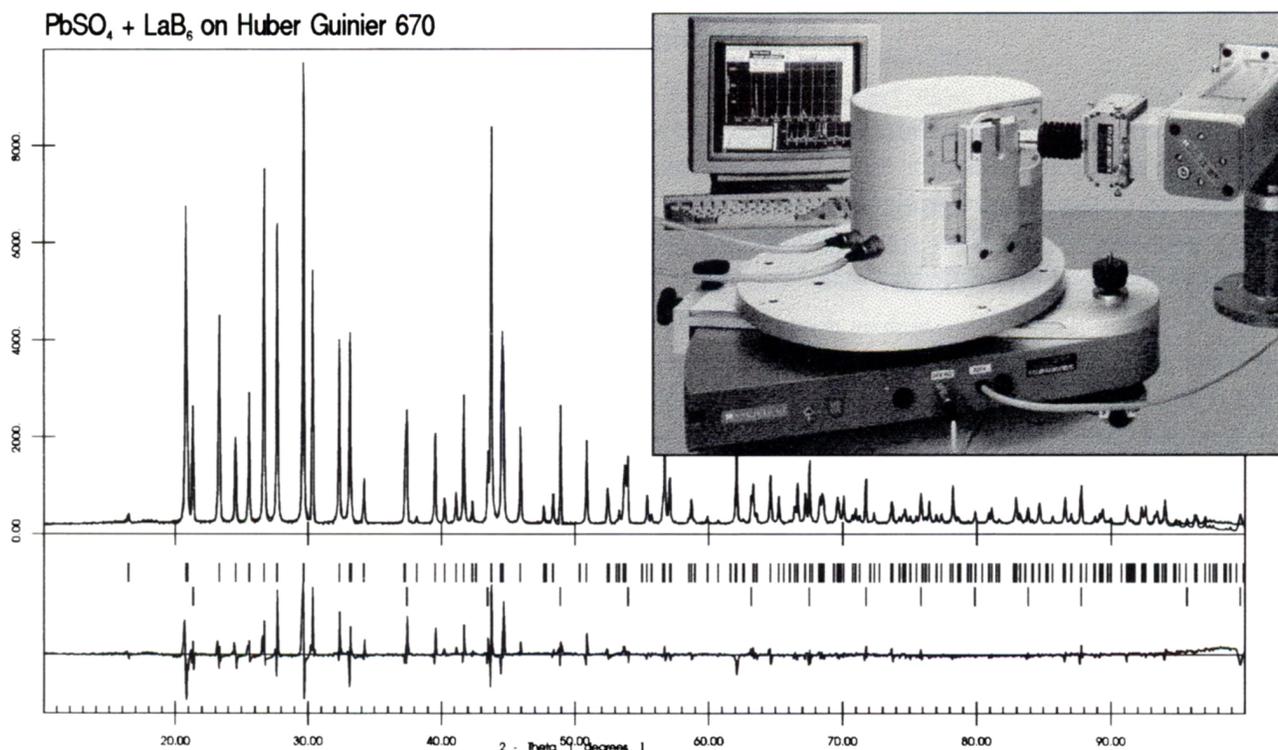
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Nathalie Audebrand will study, "Structure, Microstructure and Temperature Dependent Diffraction Studies on New Cerium-based Precursors and Related Oxides." Studies of "Structure Determination of the flk2/flt3 Ligand", will be conducted by Savvas Savvides. David Teter's research focuses on "Superhard Carbon Boronitride Alloys: A Rational Approach to Design and Synthesis." Hongwu Xu will continue his studies entitled, "Structural Analyses of Stuffed Quartz Phases Along the LiAlSiO<sub>4</sub>-SiO<sub>2</sub> Join."

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